

ACTS245MS

Radiation Hardened Octal Non-Inverting Bidirectional Bus Transceiver

Pinouts

А7 г

GND -

77

22

9

10

12 -77

11

77

B6

- B7

January 1996

Features

- Devices QML Qualified in Accordance with MIL-PRF-38535
- · Detailed Electrical and Screening Requirements are Contained in SMD# 5962-96719 and Intersil' QM Plan
- 1.25 Micron Radiation Hardened SOS CMOS
- Single Event Upset (SEU) Immunity: <1 x 10⁻¹⁰ Errors/Bit/Day (Typ)

- Latch-Up Free Under Any Conditions
- Military Temperature Range-55°C to +125°C
- Significant Power Reduction Compared to ALSTTL Logic
- DC Operating Voltage Range 4.5V to 5.5V
- Input Logic Levels
 - VIL = 0.8V Max
 - VIH = VCC/2 Min
- Input Current ≤ 1µA at VOL, VOH
- Fast Propagation Delay 18ns (Max), 12ns (Typ)

Description

The Intersil ACTS245MS is a Radiation Hardened octal non-inverting bidirectional bus transceiver intended for two-way asynchronous communication between data busses.

The ACTS245MS utilizes advanced CMOS/SOS technology to achieve high-speed operation. This device is a member of a radiation hardened. high-speed, CMOS/SOS Logic Family.

The ACTS245MS is supplied in a 20 lead Ceramic Flatpack (K suffix) or a Dual-In-Line Ceramic Package (D suffix).

20 PIN CERAMIC DUAL-IN-LINE, MIL-STD-1835 **DESIGNATOR CDIP2-T20. LEAD FINISH C** TOP VIEW 20 VCC DIR 1 A0 2 19 OE A1 3 18 B0 17 B1 A2 4 16 B2 5 A3 15 B3 A4 6 14 B4 A5 7 A6 8 13 B5 12 B6 A7 9 11 B7 GND 10 20 PIN CERAMIC FLATPACK, MIL-STD-1835 **DESIGNATOR CDFP4-F20, LEAD FINISH C** TOP VIEW 1 20 -)/-А0 г **?**> 2 19 ⊐≿ **д В0** A1 r ?? 3 18 22 A2 r ->> 4 17 ¬ B1 72 А3 г 5 16 B2 ר 22 <u> 77</u> А4 г 6 15 ¬ B3 77 72 7 ⊐ B4 А5 г ッン 14 ンと A6 r 22 8 13 22 п В5

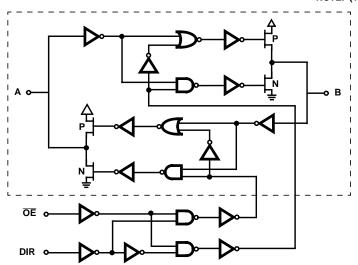
Ordering Information

PART NUMBER	TEMPERATURE RANGE	SCREENING LEVEL	PACKAGE
5962F9671901VRC	-55°C to +125°C	MIL-PRF-38535 Class V	20 Lead SBDIP
5962F9671901VXC	-55°C to +125°C	MIL-PRF-38535 Class V	20 Lead Ceramic Flatpack
ACTS245D/Sample	25°C	Sample	20 Lead SBDIP
ACTS245K/Sample	25°C	Sample	20 Lead Ceramic Flatpack
ACTS245HMSR	25°C	Die	Die

CAUTION: These devices are sensitive to electrostatic discharge; follow proper IC Handling Procedures. http://www.intersil.com or 407-727-9207 | Copyright © Intersil Corporation 1999

Functional Diagram

NOTE: (1 of 8)



TRUTH TABLE

INP		
ŌĒ	DIR	OPERATION
L	L	B Data to A Bus
L	Н	A Data to B Bus
Н	Х	Isolation

NOTE:

H = High Voltage Level, L = Low Voltage Level, X = Immaterial

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Die Characteristics

DIE DIMENSIONS:

96 mils x 117 mils 2.44 x 2.97 mm

METALLIZATION:

Type: AlSi Metal 1 Thickness: 7.125kÅ ±1.125kÅ Metal 2 Thickness: 9kÅ ±1kÅ

GLASSIVATION:

Type: SiO₂ Thickness: 8kÅ ±1kÅ

WORST CASE CURRENT DENSITY: <2.0 x 10⁵A/cm²

BOND PAD SIZE:

110μm x 110μm 4.4 mils x 4.4 mils

Metallization Mask Layout

